

General Description

SFGMOS[®]

$R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. The high V_{th} series is specially optimized for high systems with gate driving voltage greater than 10V.

Features

- Low $R_{DS(ON)}$ & FOM
- Extremely low switching loss
- Excellent stability and uniformity
- Fast switching and soft recovery

Applications

- Switched mode power supply
- Motor driver
- Battery protection
- DC-DC convertor
- Solar inverter
- UPS and energy inverter

Key Performance Parameters

Parameter	Value	Unit
$V_{DS, min} @ T_{j(max)}$	120	V
$I_{D, pulse}$	330	A
$R_{DS(ON), max} @ V_{GS}=10V$	6.5	
Q_g	68.9	nC

Marking Information

Product Name	Package	Marking
SFG110N12IF	TO262	SFG110N12I

Absolute Maximum Ratings at $T_j=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	V_{DS}	120	V
Gate source voltage	V_{GS}	± 20	V
Continuous drain current ¹⁾ , $T_C=25^\circ\text{C}$	I_D	110	A
Pulsed drain current ²⁾ , $T_C=25^\circ\text{C}$	$I_{D, pulse}$	330	A
Continuous diode forward current ¹⁾ , $T_C=25^\circ\text{C}$	I_S	110	A
Diode pulsed current ²⁾ , $T_C=25^\circ\text{C}$	$I_{S, pulse}$	330	A
Power dissipation ³⁾ , $T_C=25^\circ\text{C}$	P_D	192	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	400	mJ
Operation and storage temperature	T_{stg}, T_j	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	R	0.65	$^\circ\text{C/W}$
Thermal resistance, junction-ambient ⁴⁾	R	62	$^\circ\text{C/W}$

Electrical Characteristics at $T_j=25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	120			V	$V_{GS}=0\text{ V}, I_D=250\text{ A}$
Gate threshold voltage	$V_{GS(th)}$	2.0		4.0	V	$V_{DS}=V_{GS}, I_D=250\text{ A}$
Drain-source on-state resistance	$R_{DS(ON)}$		5.0	6.5		$V_{GS}=10\text{ V}, I_D=30\text{ A}$
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=20\text{ V}$
				-100		$V_{GS}=-20\text{ V}$
Drain-source leakage current	I_{DSS}			1	A	$V_{DS}=120\text{ V}, V_{GS}=0\text{ V}$

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C_{iss}		5823		pF	$V_{GS}=0\text{ V}$, $V_{DS}=50\text{ V}$, 100 kHz
Output capacitance	C_{oss}		779		pF	
Reverse transfer capacitance	C_{rss}		17.5		pF	
Turn-on delay time	$t_{d(on)}$		30.3		ns	$V_{GS}=10\text{ V}$, $V_{DS}=50\text{ V}$, R_G $I_D=25\text{ A}$
Rise time	t_r		33		ns	
Turn-off delay time	$t_{d(off)}$		59.5		ns	
Fall time	t_f		11.7		ns	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q_g		68.9		nC	$V_{GS}=10\text{ V}$, $V_{DS}=50\text{ V}$, $I_D=25\text{ A}$
Gate-source charge	Q_{gs}		18.1		nC	
Gate-drain charge	Q_{gd}		15.9		nC	
Gate plateau voltage	$V_{plateau}$		4.8		V	

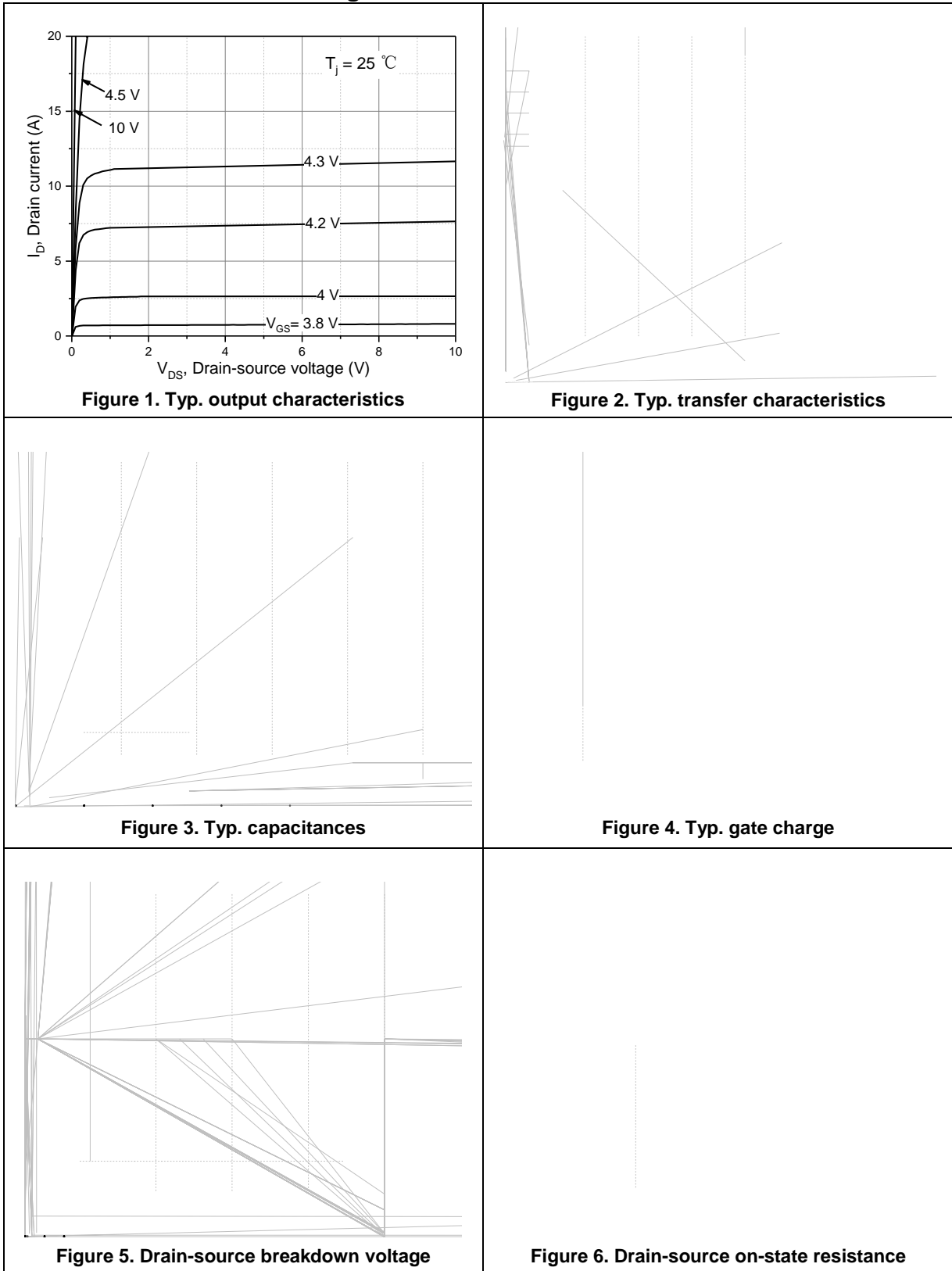
Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V_{SD}			1.3	V	$I_S=30\text{ A}$, $V_{GS}=0\text{ V}$
Reverse recovery time	t_{rr}		85		ns	$V_R=50\text{ V}$, $I_S=25\text{ A}$,
Reverse recovery charge	Q_{rr}		240		nC	
Peak reverse recovery current	I_{rrm}		4.6		A	

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of R_{θ} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ °C}$.
- 5) $V_{DD}=50\text{ V}$, $V_{GS}=10\text{ V}$, $L=0.3\text{ mH}$, starting $T_j=25\text{ °C}$.

Electrical Characteristics Diagrams



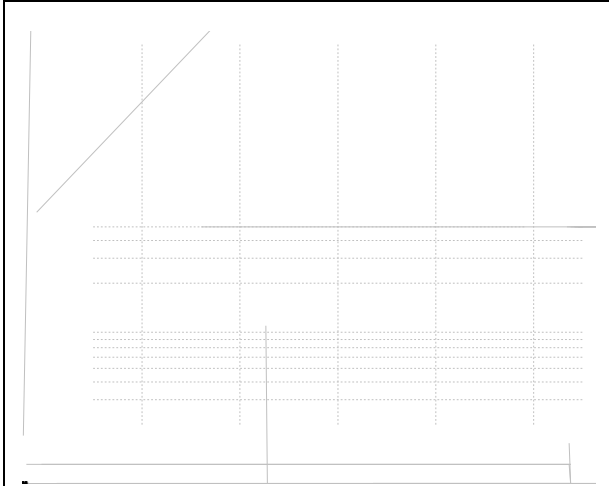


Figure 7. Forward characteristic of body diode



Figure 8. Drain current

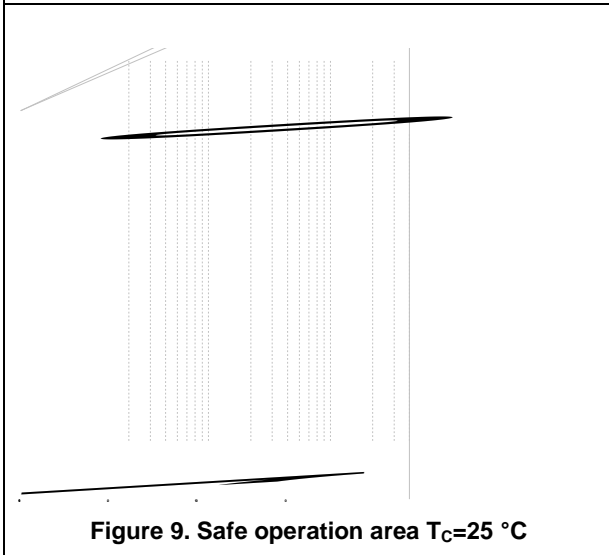


Figure 9. Safe operation area $T_c=25\text{ }^\circ\text{C}$

Test circuits and waveforms

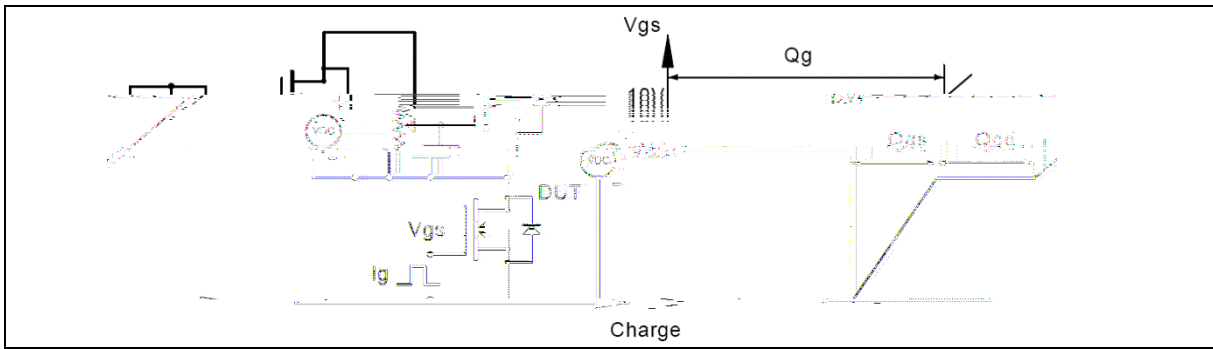


Figure 1. Gate charge test circuit & waveform

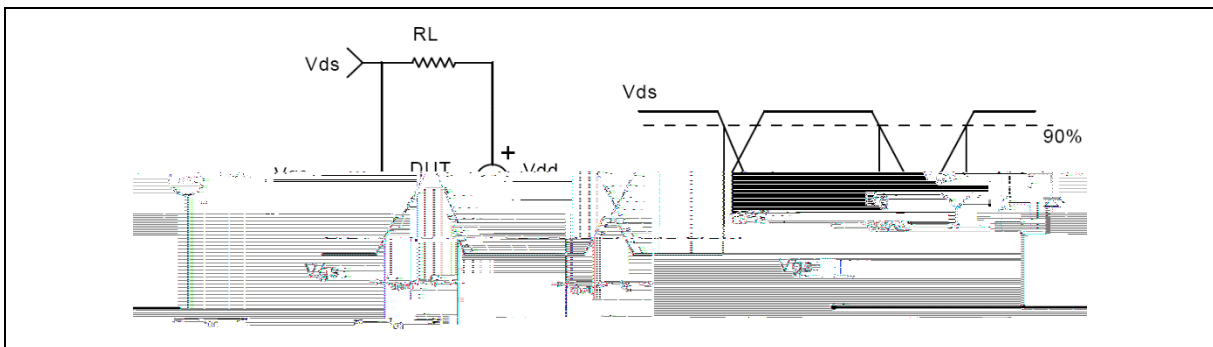


Figure 2. Switching time test circuit & waveforms

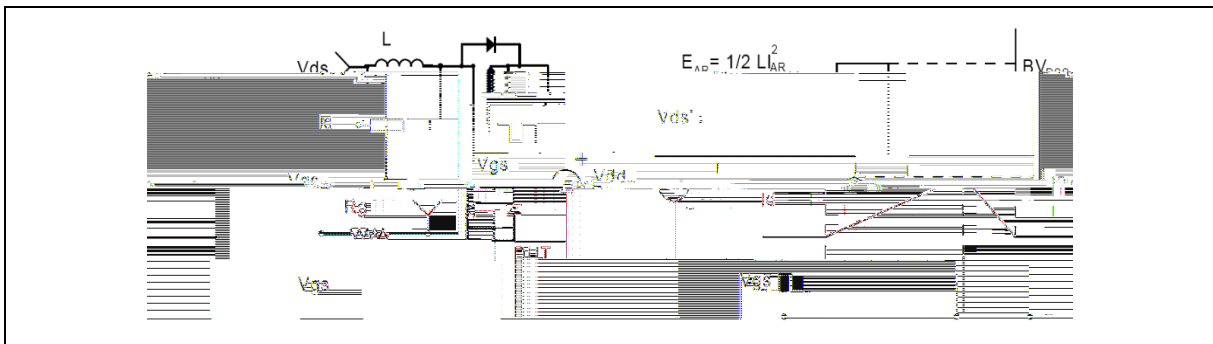


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

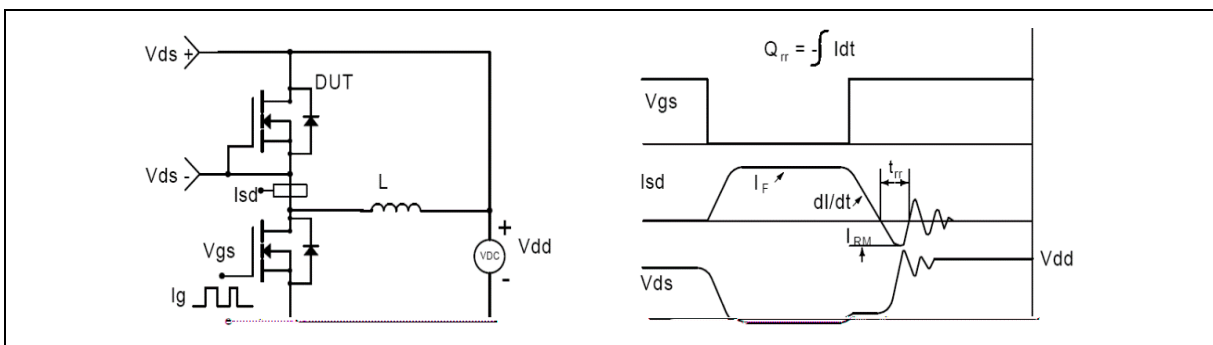
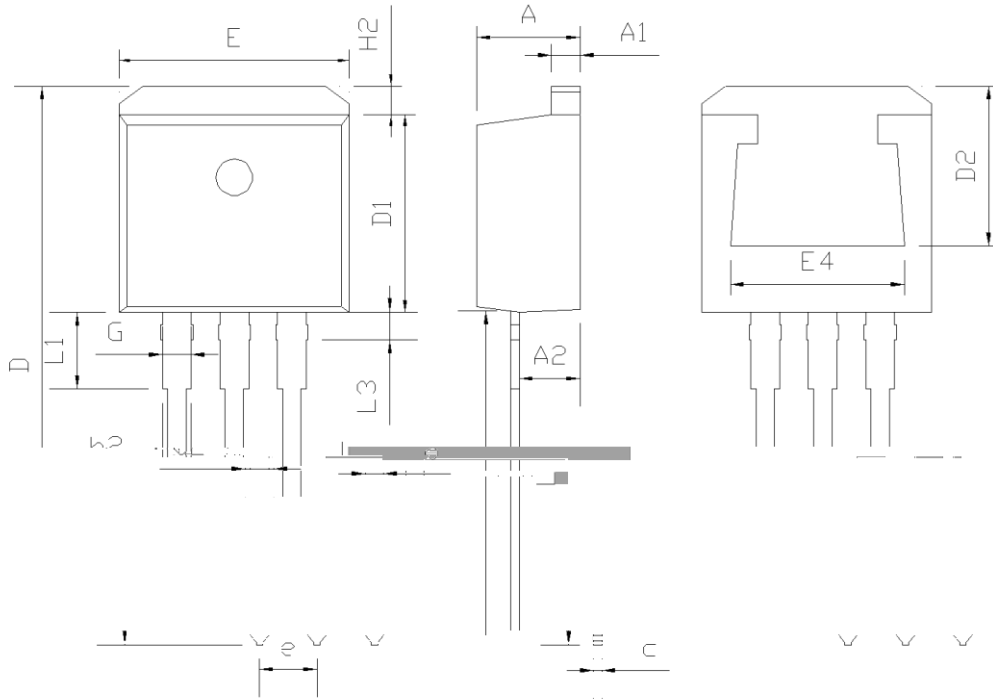


Figure 4. Diode reverse recovery test circuit & waveforms

Package Information



Symbol	mm		
	Min	Nom	Max
A	4.34	4.57	4.77
A1	1.22	1.27	1.42
A2	2.49	2.69	2.89
b	0.71	0.81	0.96
b2	1.17	1.27	1.42
c	0.28	0.38	0.53
D	23.20	23.70	24.02
D1	8.50	8.70	8.90
D2	6.00	-	-
E	9.86	10.16	10.36
E4	7.06	-	-
e	2.54 BSC		
H2	-	-	1.50
L	13.33	13.73	14.13
L1	3.50	3.75	4.00
L3	1.28	1.43	1.58
G	1.25	1.35	1.50

Version 1: TO262-C package outline dimension

Ordering Information

Package Type	Units/ Tube	Tubes / Inner Box	Units/ Inner Box	Inner Boxes/ Carton Box	Units/ Carton Box
TO262-C	50	20	1000	6	6000